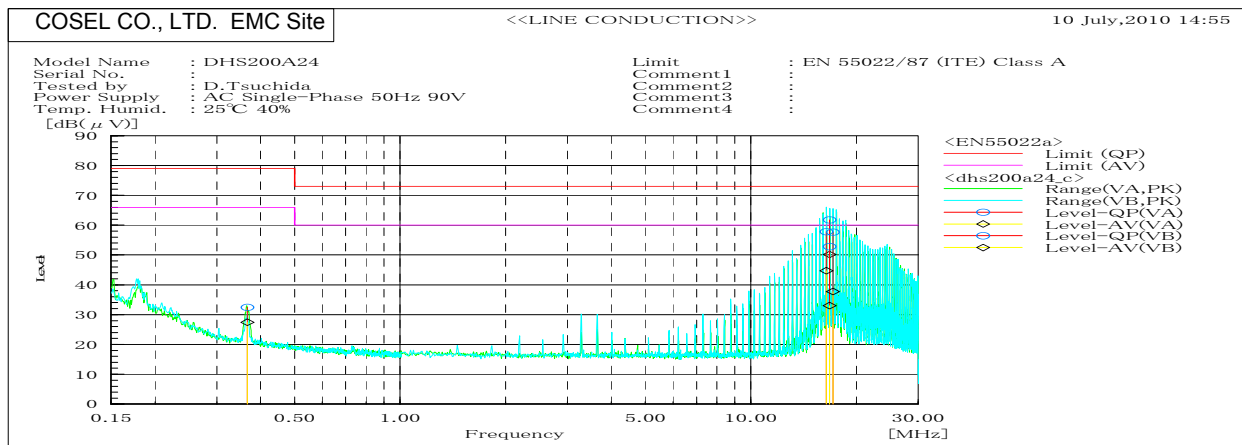
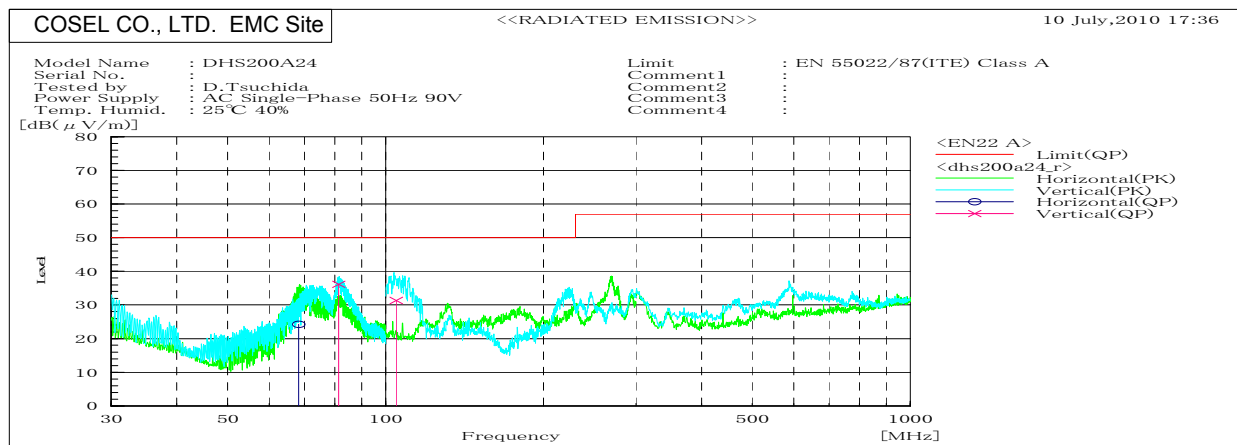


DATA SHEET		Date	10-Aug-10
Model	DHS200A24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida



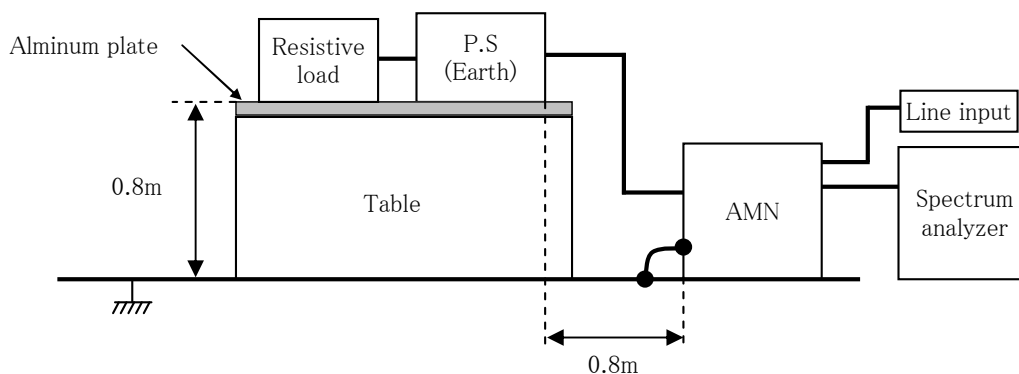
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.36702		VA	22.4	17.4	10	32.4	27.4	79	66	46.6	38.6	Pass	
16.4251		VB	47.2	34.2	10.6	57.8	44.8	73	60	15.2	15.2	Pass	
16.7717		VB	42.2	22.4	10.6	52.8	33	73	60	20.2	27	Pass	
16.7819		VA	51.2	39.6	10.6	61.8	50.2	73	60	11.2	9.8	Pass	
17.1364		VB	47.1	27.1	10.6	57.7	37.7	73	60	15.3	22.3	Pass	



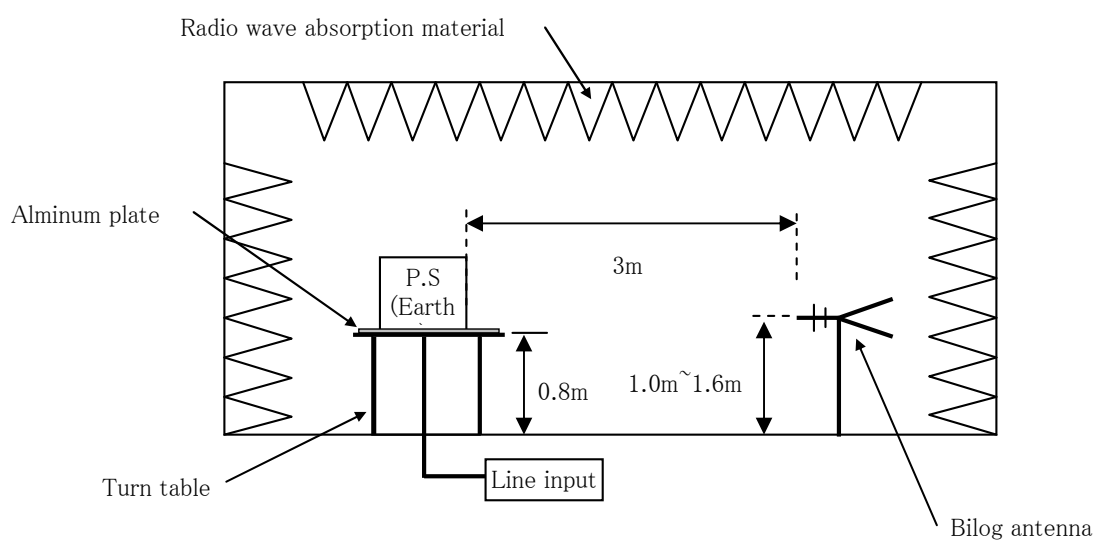
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP			QP		QP				
68.293	H	Stable	45.9		-21.7	24.2		50	25.8	150	346	
81.427	V	Stable	56.4		-20.2	36.2		50	13.8	124	89	
104.778	V	Stable	48.7		-17.3	31.4		50	18.6	133	98	

DATA SHEET		Date	10-Aug-10
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Tsuchida

1. Line conduction

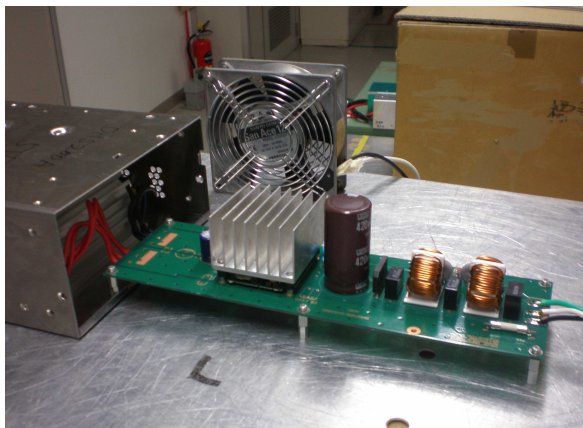


2. Radiated emission

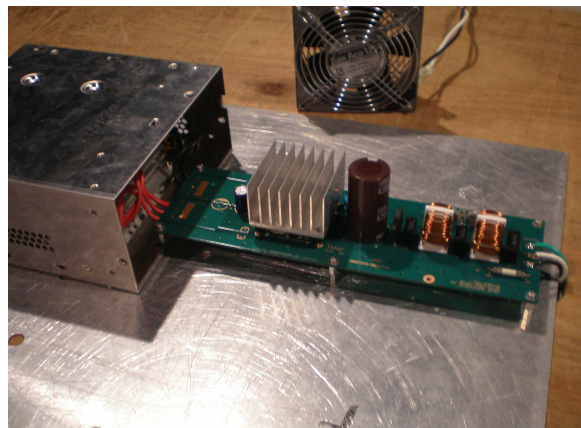


Model Name:DHS200A Series

LINE CONDUCTION



RADIATED EMISSION



C8	:	DHS200A05	10 μ F	C9	:	DHS200A05	2200 μ F
		DHS200A12	10 μ F			DHS200A12	1000 μ F
		DHS200A15	10 μ F			DHS200A15	1000 μ F
		DHS200A24	4.7 μ F			DHS200A24	470 μ F